

CMOS Digital Integrated Circuits Silicon Monolithic

# TC7WH125FU

#### 1. Functional Description

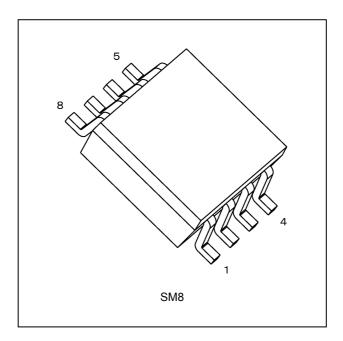
• Dual Bus Buffer with 3-State Output

#### 2. Features

- (1) Wide operating temperature range:  $T_{opr} = -40$  to 125 °C (Note 1)
- (2) High speed operation:  $t_{pd} = 3.8 \text{ ns (typ.)}$  ( $V_{CC} = 5.0 \text{ V}$ ,  $C_L = 15 \text{ pF}$ )
- (3) Low power dissipation:  $I_{CC}$  = 2.0  $\mu A$  (max) ( $T_a$  = 25  $^{\circ}C$ )
- (4) High noise immunity:  $V_{NIH} = V_{NIL} = 28 \% V_{CC}$  (min)
- (5) 5.5 V tolerant inputs
- (6) Wide operating voltage range:  $V_{CC} = 2.0$  to 5.5 V
- (7) Low noise:  $V_{OLP} = 0.8 \text{ V (max)}$

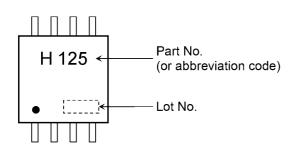
Note 1: For devices with the ordering part number ending in J(CT.  $T_{opr}$  = -40 to 85 °C for the other devices.

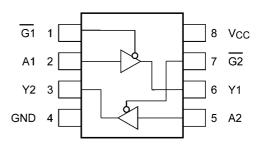
#### 3. Packaging





#### 4. Marking and Pin Assignment





Marking

Pin Assignment (Top view)

#### 5. IEC Logic Symbol



#### 6. Truth Table

G	А	Y
Н	X	Z
L	L	L
L	Н	Н

X: Don't care

Z: High impedance

## 7. Absolute Maximum Ratings (Note) (Unless otherwise specified, $T_a = 25$ °C)

Characteristics	Symbol	Note	Rating	Unit
Supply voltage	V <sub>CC</sub>		-0.5 to 7.0	V
Input voltage	V <sub>IN</sub>		-0.5 to 7.0	
DC output voltage	V <sub>OUT</sub>		-0.5 to V <sub>CC</sub> + 0.5	
Input diode current	I <sub>IK</sub>		-20	mA
Output diode current	l <sub>ok</sub>	(Note 1)	±20	
DC output current	I <sub>OUT</sub>		±25	
V <sub>CC</sub> /ground current	I <sub>CC</sub>		±50	
Power dissipation	P <sub>D</sub>		300	mW
Storage temperature	T <sub>stg</sub>		-65 to 150	Ç

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: V<sub>OUT</sub> < GND, V<sub>OUT</sub> > V<sub>CC</sub>



# 8. Operating Ranges (Note)

Characteristics	Symbol	Note	Test Condition	Rating	Unit
Supply voltage	V <sub>CC</sub>		_	2.0 to 5.5	V
Input voltage	V <sub>IN</sub>		_	0 to 5.5	
Output voltage	V <sub>OUT</sub>		_	0 to V <sub>CC</sub>	
Operating temperature	T <sub>opr</sub>	(Note 1)	_	-40 to 125	°C
		(Note 2)	_	-40 to 85	
Input rise and fall time	dt/dv		$V_{CC} = 3.3 \pm 0.3 \text{ V}$	0 to 100	ns/V
			$V_{CC} = 5.0 \pm 0.5 \text{ V}$	0 to 20	

Note: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either  $V_{CC}$  or GND.

Note 1: For devices with the ordering part number ending in J(CT.

Note 2: For devices except those with the ordering part number ending in J(CT.

#### 9. Electrical Characteristics

# 9.1. DC Characteristics (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics	Symbol	Test Condition		V <sub>CC</sub> (V)	Min	Тур.	Max	Unit
High-level input voltage	V <sub>IH</sub>	_		2.0	1.5	_	_	V
				3.0 to 5.5	$V_{CC} \times 0.7$	_	_	
Low-level input voltage	V <sub>IL</sub>	_		2.0	_	_	0.5	V
				3.0 to 5.5	_	_	V <sub>CC</sub> × 0.3	
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -50 μA	2.0	1.9	2.0	_	V
				3.0	2.9	3.0	_	
				4.5	4.4	4.5	_	
			I <sub>OH</sub> = -4 mA	3.0	2.58	_	_	
			I <sub>OH</sub> = -8 mA	4.5	3.94	_	_	
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IL</sub>	I <sub>OL</sub> = 50 μA	2.0	_	0.0	0.1	V
				3.0	_	0.0	0.1	
				4.5	_	0.0	0.1	
			I <sub>OL</sub> = 4 mA	3.0	_	_	0.36	
			I <sub>OL</sub> = 8 mA	4.5	_	_	0.36	
3-state output OFF-state leakage current	I <sub>OZ</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		5.5	_	_	±0.25	μА
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND		0 to 5.5	_	_	±0.1	μΑ
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	_	2.0	μΑ



# 9.2. DC Characteristics (Unless otherwise specified, T<sub>a</sub> = -40 to 85 °C)

Characteristics	Symbol	Test Conditi	on	V <sub>CC</sub> (V)	Min	Max	Unit
High-level input voltage	V <sub>IH</sub>	_		2.0	1.5	_	V
				3.0 to 5.5	$V_{CC} \times 0.7$	_	
Low-level input voltage	V <sub>IL</sub>	_		2.0	_	0.5	V
				3.0 to 5.5		$V_{CC} \times 0.3$	
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -50 μA	2.0	1.9	_	V
				3.0	2.9	_	
				4.5	4.4	_	
			$I_{OH}$ = -4 mA	3.0	2.48	_	
			$I_{OH}$ = -8 mA	4.5	3.80	_	
Low-level output voltage	V <sub>OL</sub>	$V_{IN} = V_{IL}$	I <sub>OL</sub> = 50 μA	2.0		0.1	V
				3.0	_	0.1	
				4.5	_	0.1	
			$I_{OL}$ = 4 mA	3.0	_	0.44	
			$I_{OL}$ = 8 mA	4.5	_	0.44	
3-state output OFF-state leakage current	I <sub>OZ</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		5.5	_	±2.5	μА
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND		0 to 5.5	_	±1.0	μΑ
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	20.0	μА

# 9.3. DC Characteristics (Note) (Unless otherwise specified, T<sub>a</sub> = -40 to 125 °C)

Characteristics	Symbol	Test Condition	on	V <sub>CC</sub> (V)	Min	Max	Unit
High-level input voltage	V <sub>IH</sub>	_		2.0	1.5	_	V
				3.0 to 5.5	$V_{CC} \times 0.7$	_	
Low-level input voltage	V <sub>IL</sub>	_		2.0	_	0.5	V
				3.0 to 5.5	_	$V_{CC} \times 0.3$	
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -50 μA	2.0	1.9	_	V
				3.0	2.9	_	
				4.5	4.4	_	
			$I_{OH} = -4 \text{ mA}$	3.0	2.40	_	
			$I_{OH}$ = -8 mA	4.5	3.70	_	
Low-level output voltage	V <sub>OL</sub>	$V_{IN} = V_{IL}$	I <sub>OL</sub> = 50 μA	2.0	_	0.1	V
				3.0		0.1	
				4.5	_	0.1	
			$I_{OL} = 4 \text{ mA}$	3.0	_	0.55	
			$I_{OL}$ = 8 mA	4.5	_	0.55	
3-state output OFF-state leakage current	l <sub>OZ</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		5.5	_	±10.0	μА
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND		0 to 5.5		±2.0	μΑ
Quiescent supply current	I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	40.0	μΑ

Note: For devices with the ordering part number ending in J(CT.



### 9.4. AC Characteristics (Unless otherwise specified, $T_a = 25$ °C, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Note	Test Condition	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Тур.	Max	Unit
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		_	$3.3 \pm 0.3$	15	_	5.6	8.0	ns
					50	_	8.1	11.5	
				$5.0 \pm 0.5$	15		3.8	5.5	
					50		5.3	7.5	
3-state output enable time	t <sub>PZL</sub> ,t <sub>PZH</sub>		$R_L = 1 k\Omega$	$3.3 \pm 0.3$	15		5.4	8.0	ns
					50		7.9	11.5	
				$5.0 \pm 0.5$	15	_	3.6	5.1	
					50	_	5.1	7.1	
3-state output disable time	$t_{PLZ}, t_{PHZ}$		$R_L = 1 k\Omega$	$3.3 \pm 0.3$	50	_	9.5	13.2	ns
				$5.0 \pm 0.5$	50	_	6.1	8.8	
Output skew	t <sub>osLH</sub> ,t <sub>osHL</sub>	(Note 1)	_	$3.3 \pm 0.3$	50			1.5	ns
				$5.0 \pm 0.5$	50	_	_	1.0	
Input capacitance	C <sub>IN</sub>		_			_	4	10	pF
Output capacitance	C <sub>OUT</sub>						6	_	pF
Power dissipation capacitance	C <sub>PD</sub>	(Note 2)				_	14	_	pF

Note 1: Parameter guaranteed by design.  $(t_{osLH} = |t_{PLH}m-t_{PLH}n|, t_{osHL} = |t_{PHL}m-t_{PHL}n|)$ 

Note 2:  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation.  $I_{CC(opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2 \text{ (per 1 bit)}$ 

# 9.5. AC Characteristics (Unless otherwise specified, $T_a = -40$ to 85 °C, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Note	Test Condition	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Max	Unit
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		_	$3.3 \pm 0.3$	15	1.0	9.5	ns
					50	1.0	13.0	
				5.0 ± 0.5	15	1.0	6.5	
					50	1.0	8.5	
3-state output enable time	t <sub>PZL</sub> ,t <sub>PZH</sub>		$R_L = 1 k\Omega$	$3.3 \pm 0.3$	15	1.0	9.5	ns
					50	1.0	13.0	
				5.0 ± 0.5	15	1.0	6.0	
					50	1.0	8.0	
3-state output disable time	t <sub>PLZ</sub> ,t <sub>PHZ</sub>		$R_L = 1 k\Omega$	$3.3 \pm 0.3$	50	1.0	15.0	ns
				5.0 ± 0.5	50	1.0	10.0	
Output skew	t <sub>osLH</sub> ,t <sub>osHL</sub>	(Note 1)	_	$3.3\pm0.3$	50	_	1.5	ns
				5.0 ± 0.5	50	_	1.0	
Input capacitance	C <sub>IN</sub>		_			_	10	pF

Note 1: Parameter guaranteed by design.  $(t_{osLH} = |t_{PLH}m-t_{PLH}n|, t_{osHL} = |t_{PHL}m-t_{PHL}n|)$ 



# 9.6. AC Characteristics (Note) (Unless otherwise specified, $T_a = -40$ to 125 °C, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Note	Test Condition	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Max	Unit
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		_	$3.3\pm0.3$	15	1.0	11.0	ns
					50	1.0	14.5	
				5.0 ± 0.5	15	1.0	7.5	
					50	1.0	9.5	
3-state output enable time	$t_{PZL}, t_{PZH}$		$R_L = 1 k\Omega$	$3.3\pm0.3$	15	1.0	11.0	ns
					50	1.0	14.5	
				$5.0 \pm 0.5$	15	1.0	7.0	
					50	1.0	9.0	
3-state output disable time	$t_{PLZ}, t_{PHZ}$		R <sub>L</sub> = 1 kΩ	$3.3\pm0.3$	50	1.0	16.5	ns
				$5.0 \pm 0.5$	50	1.0	11.0	
Output skew	t <sub>osLH</sub> ,t <sub>osHL</sub>	(Note 1)	_	$3.3\pm0.3$	50	_	1.5	ns
				5.0 ± 0.5	50	_	1.0	
Input capacitance	C <sub>IN</sub>		_			_	10	pF

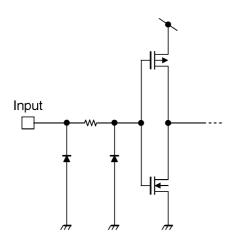
Note: For devices with the ordering part number ending in J(CT.

Note 1: Parameter guaranteed by design. ( $t_{osLH} = |t_{PLH}m - t_{PLH}n|$ ,  $t_{osHL} = |t_{PHL}m - t_{PHL}n|$ )

# 9.7. Noise Characteristics (Unless otherwise specified, $T_a = 25$ °C, Input: $t_f = t_f = 3$ ns)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Тур.	Limit	Unit
Quiet output maximum dynamic V <sub>OL</sub>	V <sub>OLP</sub>	C <sub>L</sub> = 50 pF	5.0	0.3	0.8	V
Quiet output minimum dynamic V <sub>OL</sub>	V <sub>OLV</sub>	C <sub>L</sub> = 50 pF	5.0	-0.3	-0.8	V
Minimum high-level dynamic input voltage	$V_{IHD}$	C <sub>L</sub> = 50 pF	5.0		3.5	V
Maximum low-level dynamic input voltage	$V_{ILD}$	C <sub>L</sub> = 50 pF	5.0		1.5	V

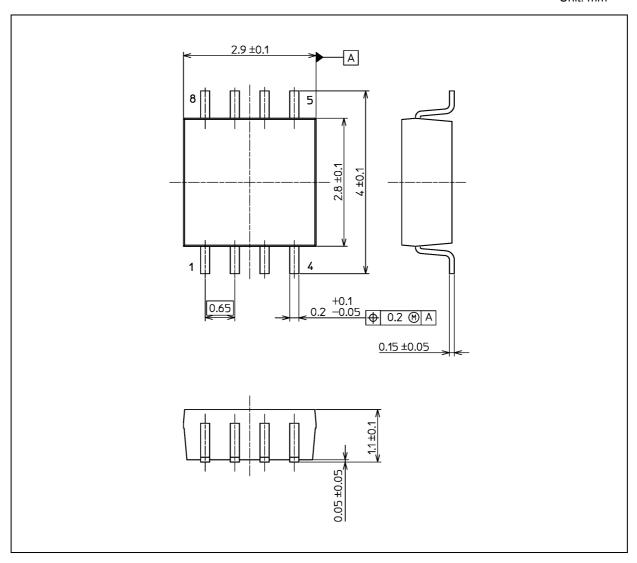
### 10. Input Equivalent Circuit





### **Package Dimensions**

Unit: mm



Weight: 21 mg (typ.)

	Package Name(s)	
JEDEC: SOT-505		
Nickname: SM8		



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